



FORM PTO-1449

Sheet 1 of 1

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				Atty Docket No. IL-10610	Serial No. 09/827,454		
INFORMATION DISCLOSURE STATEMENT STATEMENT BY APPLICANT (use several sheets if necessary)				Applicant Anthony J. Ruggiero		Group	
				Filing Date 4/6/01		Examiner Technology Center 2600	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
u	1	5,038,359	8/6/91	Pepper, et al.	372	99	
u	2	5,140,463	8/18/92	Yoo, et al.	359	559	
u	3	5,371,368	12/6/94	Alfano, et al.	250	341.1	
u	4	5,451,785	9/19/95	Faris	250	330	
u	5	5,519,723	5/21/96	MacDonald	372	99	
u	6	5,576,627	11/19/96	McEwan	324	639	
u	7	5,578,185	11/26/96	Bergeron, et al.	205	123	
u	8	5,625,458	4/29/97	Alfano, et al.	356	446	
u	9	5,738,101	4/14/98	Sappey	128	665	
u	10	5,936,739	8/10/99	Cameron, et al.	356	441	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation YES NO
u	A	EP 0 801 452 A2	15 SEP 97	EPO	H01S 3	25	
OTHER DISCLOSURES (including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)							
u	1.1		P. Kurz, et al., "Highly efficient phase conjugation using spatially nondegenerate four-wave mixing in a broad-area laser diode," Feb. 26, 1996, Appl. Phys. Lett. 68, (9) pp. 1180-1182				
u	1.2		R. Hui, et al., "Optical Frequency Conversion Using Nearly Degenerate Four-Wave Mixing in a Distributed-Feedback Semiconductor Laser: Theory and Experiment," Dec. 1993, Journal of Lightwave Technology, Vol. 11, No. 12, pp. 2026-2032				
u	1.3		R. W. Schirmer, et al., "Quantum theory of noise in phase conjugation by four-wave mixing in a two-level system," April 1997, Physical Review A, pp. 3155-3163				
u	1.4		D. H. DeTienne, et al., "Semiconductor Laser Dynamics for Feedback from a Finite-Penetration-Depth Phase-Conjugate Mirror," May 1997, IEEE Journal of Quantum Electronics, Vol. 33, No. 5, pp. 838-844				
u	1.5		M. Lucente, et al., "Spatial and frequency dependence of four-wave mixing in broad-area diode lasers," Nov. 14, 1988, Appl. Phys. Lett 53 (20), pp. 1897-1899				
Examiner				8/16/01			
Examiner: initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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